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INCITS/ISO/IEC 10373-3:2010 (R2016)

*Identification cards - Test methods - Part 3:
Integrated circuit cards with contacts and
related interface devices*

Developed by



Where IT all begins



INCITS/ISO/IEC 10373-3:2010[2011]

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Identification cards — Test methods — Part 3: Integrated circuit cards with contacts and related interface devices

Cartes d'identification — Méthodes d'essai —

*Partie 3: Cartes à circuit(s) intégré(s) à contacts et dispositifs d'interface
assimilés*

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Contents

Page

Foreword	v
1 Scope	1
2 Normative references	1
3 Terms and definitions	2
4 General items applicable to the test methods	2
4.1 Test environment	2
4.2 Pre-conditioning	2
4.3 Selection of test methods	3
4.4 Default tolerance	3
4.5 Total measurement uncertainty	3
4.6 Conventions for electrical measurements	3
4.7 Apparatus	3
4.7.1 Apparatus for testing the integrated circuit cards with contacts (card-test-apparatus)	3
4.7.2 Apparatus for testing the interface device (IFD-test-apparatus)	8
4.7.3 Test Scenario	13
4.8 Relationship of test methods versus base standard requirements	13
5 Test methods for electrical characteristics of cards with contacts	16
5.1 VCC contact	16
5.1.1 Apparatus	16
5.1.2 Procedure	16
5.1.3 Test report	17
5.2 I/O contact	17
5.2.1 Apparatus	17
5.2.2 Procedure	17
5.2.3 Test report	19
5.3 CLK contact	19
5.3.1 Apparatus	19
5.3.2 Procedure	19
5.3.3 Test report	20
5.4 RST contact	20
5.4.1 Apparatus	20
5.4.2 Procedure	20
5.4.3 Test report	21
5.5 SPU (C6) contact	21
6 Test methods for logical operations of cards with contacts	21
6.1 Answer to Reset (ATR)	21
6.1.1 Cold Reset and Answer-to-Reset (ATR)	21
6.1.2 Warm Reset	22
6.2 T=0 Protocol	22
6.2.1 I/O transmission timing for T=0 protocol	22
6.2.2 I/O character repetition for T=0 protocol	23
6.2.3 I/O reception timing and error signaling for T=0 protocol	24
6.3 T=1 Protocol	25
6.3.1 I/O transmission timing for T=1 protocol	25
6.3.2 I/O reception timing for T=1 protocol	25
6.3.3 Character Waiting Time (CWT) behavior	26
6.3.4 card-reaction to IFD exceeding character waiting time (CWT)	27
6.3.5 Block Guard time (BGT)	27
6.3.6 Block sequencing by the card	28

This is a preview of "INCITS/ISO/IEC 10373...". [Click here to purchase the full version from the ANSI store.](#)

6.3.7	Reaction of the card to protocol errors	31
6.3.8	Recovery of a transmission error by the card	31
6.3.9	Resynchronization	32
6.3.10	IFSD negotiation	33
6.3.11	Abortion by the IFD	34
7	Test methods for physical and electrical characteristics of the IFD	35
7.1	Activation of contacts	35
7.1.1	Apparatus	35
7.1.2	Procedure	35
7.1.3	Test report	35
7.2	VCC contact	36
7.2.1	Apparatus	36
7.2.2	Procedure	36
7.2.3	Test report	37
7.3	I/O contact	37
7.3.1	Apparatus	37
7.3.2	Procedure	37
7.3.3	Test report	39
7.4	CLK contact	39
7.4.1	Apparatus	39
7.4.2	Procedure	39
7.4.3	Test report	41
7.5	RST contact	41
7.5.1	Apparatus	41
7.5.2	Procedure	41
7.5.3	Test report	42
7.6	SPU (C6) contact	42
7.7	Deactivation of the contacts	42
7.7.1	Apparatus	42
7.7.2	Procedure	42
7.7.3	Test report	43
8	Test methods for logical operations of the IFD	43
8.1	Answer to Reset (ATR)	43
8.1.1	Card Reset (cold reset)	43
8.1.2	card Reset (warm reset)	43
8.2	T=0 Protocol	44
8.2.1	I/O transmission timing for T=0 protocol	44
8.2.2	I/O character repetition for T=0 protocol	44
8.2.3	I/O reception timing and error signaling for T=0 protocol	45
8.3	T=1 Protocol	46
8.3.1	I/O transmission timing for T=1 protocol	46
8.3.2	I/O reception timing for T=1 protocol	47
8.3.3	IFD Character Waiting Time (CWT) behavior	48
8.3.4	IFD-reaction to card exceeding CWT	49
8.3.5	Block Guard time (BGT)	49
8.3.6	Block sequencing by the IFD	50
8.3.7	Recovery of a transmission error by the IFD	52
8.3.8	IFSC negotiation	53
8.3.9	Abortion by the card	53
8.4	IFD — Reaction of the IFD to invalid PCBs	54
8.4.1	Apparatus	54
8.4.2	Procedure	54
8.4.3	Test report	55

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Foreword

ISO (the International Organization for Standardization) and IEC (the International Electrotechnical Commission) form the specialized system for worldwide standardization. National bodies that are members of ISO or IEC participate in the development of International Standards through technical committees established by the respective organization to deal with particular fields of technical activity. ISO and IEC technical committees collaborate in fields of mutual interest. Other international organizations, governmental and non-governmental, in liaison with ISO and IEC, also take part in the work. In the field of information technology, ISO and IEC have established a joint technical committee, ISO/IEC JTC 1.

International Standards are drafted in accordance with the rules given in the ISO/IEC Directives, Part 2.

The main task of the joint technical committee is to prepare International Standards. Draft International Standards adopted by the joint technical committee are circulated to national bodies for voting. Publication as an International Standard requires approval by at least 75 % of the national bodies casting a vote.

Attention is drawn to the possibility that some of the elements of this document may be the subject of patent rights. ISO and IEC shall not be held responsible for identifying any or all such patent rights.

ISO/IEC 10373-3 was prepared by Joint Technical Committee ISO/IEC JTC 1, *Information technology*, Subcommittee SC 17, *Cards and personal identification*.

This second edition cancels and replaces the first edition (ISO/IEC 10373-3:2001), which has been technically revised.

ISO/IEC 10373 consists of the following parts, under the general title *Identification cards — Test methods*:

- *Part 1: General characteristics*
- *Part 2: Cards with magnetic stripes*
- *Part 3: Integrated circuit cards with contacts and related interface devices*
- *Part 5: Optical memory cards*
- *Part 6: Proximity cards*
- *Part 7: Vicinity cards*
- *Part 8: USB-ICC*

The following part is under preparation:

- *Part 9: Optical memory cards: Holographic recording method*